



2026 Program Agenda

Monday, 11 May 2026				
Time (PST)	Session	Title	Speaker	Organization
11:00 AM	Registration, 11:00 AM to 4:00 PM (upstairs) and 5:00 to 8:00 PM (Soledad Ballroom, downstairs)			
1:00 PM	Intro	Opening Remarks	Justin Likar George Tzintzarov	JHU/APL, The Aerospace Corporation
1:10 PM	New Effects and Efforts	Session Intro	Sergeh Vartanian	Relativity Space
1:20 PM		SEE Test Methodology for Systematic Upscreening of COTS Devices	Stephen Martinez	TRAD Inc.
1:40 PM		SEHE Effects 7nm and 4nm AI SoCs	Douglas Sheldon	Jet Propulsion Laboratory
2:00 PM		Effects of Electrical Program/Erase Cycling on the Single-Event Response of 65 nm SONOS Charge-Trap	Adam Hubbard	Indiana University
2:20 PM		RadSim: A Lightweight Framework for Simulation of Single-Event Upsets in Arbitrarily Complex ICs	John Barney	Indiana University
2:40 PM		CARRE: The Center for Advancing the Radiation Resilience of Electronics	James Trippe	Vanderbilt University
3:00 PM	Break			
3:30 PM	Invited	Invited Talk Single Event Effects in the Starlink Mega-Constellation: On-Orbit Observations from 10,000 Satellites	Henry Tokar	SpaceX
4:10 PM	Testing Techniques	Session Intro	Adalin Benedetto	Alphacore
4:20 PM		Predicting the Location of Heavy Ion Interactions within Analog Components	Jake Carpenter	Indiana University
4:40 PM		Benchtop Emulation of System-Level Analog Single-Event Transients from Piece-Part Data	Matthew McKinney	Indiana University
5:00 PM		Fully Automated Shutter Testing (FAST) for Single-Event Effects (SEE)	Evan Agarwal	NASA JSC (Amentum)
5:20 PM	End of Monday Events			
5:45 to 7:15 PM	Welcome Reception and Registration (Soledad Ballroom)			

2026 SEE-SoCS Program Agenda

Tuesday, 12 May 2026

Time (PST)	Session	Title	Speaker	Organization
7:30 AM	Registration, 7:30 AM to 4:00 PM			
8:10 AM	Facilities	Session Intro	Scott Davis	The Aerospace Corporation
8:20 AM		The K150 Cyclotron Upgrade and Cyclotron Institute Building Expansion Projects at TAMU	Henry Clark	Texas A&M University
8:40 AM		High-Energy Heavy Ion Testing in HEARTS@CERN: possibilities and challenges	Natalia Emriskova	CERN
9:00 AM		RADNEXT 2030 EU-program: Europe's coordinated access to radiation effects testing facilities	Gerd Datzmann	Datzmann Interact & Innovate
9:20 AM		Development and Start-up of the K500 SEE Test Facility at MSU	Steve Lidia	Michigan State University
9:40 AM		Unofficial Domestic U.S. Heavy Ion Capacity and Demand	Kenneth LaBel	Trusted Strategic Solutions, LLC
10:00 AM		Break		
10:30 AM	Facilities	The Importance of ECR Ion Sources for Heavy Ion Accelerators	Janilee Benitez	Lawrence-Berkeley National Laboratory
10:50 AM		Space Electronics Testing at BNL: a Status Report	Kevin Brown	Brookhaven National Laboratory
11:10 AM		The Constraint Surface of Proton Radiation Effects Testing: One Year of Operational Usage Patterns	Eric O'Quinn	ProNova Solutions
11:30 AM	Lunch			
1:00 PM	Alternative SEE Testing	Session Intro	Dale McMorrow	U.S. Naval Research Laboratory
1:10 PM		STELLARBeam	Jason Thieman	Northrop Grumman
1:30 PM		High-energy x-ray source for alternative SEE tests	Stephen Coleman	RadiaSoft
1:50 PM		Progress on Pulsed Electrons as an Alternative to Heavy-Ion SEE Testing	Atharva Kulkarni	UCLA Particle Beam Physics Lab
2:10 PM		Verifying Surrogate Sources for Single-Event Effects Testing	Joel Hales	U.S. Naval Research Laboratory
2:30 PM		Northrop Grumman's PULSEE Lab Upgrades and Recent Results	Jeffrey Warner	Northrop Grumman Corporation
2:50 PM		Characterizing the Operating Parameters for Pulsed Laser SEE Testing	Trevor Crane	U.S. Naval Research Laboratory
3:10 PM	Break			
3:30 PM	Invited	Invited Talk Cause and Effect: Using on orbit anomalies to improve space weather knowledge, monitoring, and resilience	Janet Green	Aerospace Corporation
4:10 PM	Panel Discussion: AI for Accelerators Moderator: Krysten Pfau, Lockheed Martin Panelists: Janilee Benitez, Lawrence-Berkeley National Laboratory Steve Lidia, Michigan State University Kevin Brown, Brookhaven National Laboratory Henry Clark, Texas A&M University			
5:00 PM	End of Tuesday Events			

2026 SEE-SoCS Program Agenda

Wednesday, 13 May 2026

Time (PST)	Session	Title	Speaker	Organization
7:30 AM	Registration, 7:30 AM to 4:00 PM			
8:10 AM	Wide Bandgap Semiconductors	Session Intro	Sajal Islam	Indiana University
8:20 AM	Invited	Invited Talk Basic mechanisms of single-event effects in wide-bandgap power devices: an overview of SiC and GaN technologies	Corinna Martinella	University of Montpellier
9:00 AM	Wide Bandgap Semiconductors	SEE Testing of Latest Generation Rad Hard Low Voltage GaN HEMTs	Rob Strittmatter	EPC Space
9:20 AM		SEE test results of various generation of GaN HEMT	Mauricio Cano	Infineon
9:40 AM		Pulsed-Laser Single-Event Effects Study of Wide-Bandgap and Ultrawide Bandgap Semiconductors	Ani Khachatrian	US Naval Research Laboratory
10:00 AM	Break			
10:30 AM	Wide Bandgap Semiconductors	Geometry- and Power-Rating-Dependent Heavy-Ion Induced Single-Event Effects in Enhancement-Mode GaN	Herb Gingold	University of Central Florida (Radiation Effects Exploration Lab)
10:50 AM	Community Efforts	Session Intro	Mitra Yoonessi	General Atomics
11:00 AM		Modernizing Radiation Effects Community Infrastructure	Kenneth LaBel	Trusted Strategic Solutions, LLC
11:20 AM		Tech Demos & Rapid Prototyping: Best Practices and Approaches for Proton SEE at System Level	Justin Likar	Johns Hopkins University Applied Physics Laboratory
11:40 AM	Lunch			
1:10 PM	Community Efforts	RAD-TECH: A Research Portfolio to Enable State-of-the-Art Electronics in Radiation Environments	John Dickinson	Sandia National Laboratories
1:30 PM		Developing Radiation Effects Talent Through Air Force Research Laboratory and University of New Mexico Collaboration	Ben Rutherford	COSMIAC
1:50 PM	SoCS	SoCS Intro	Ian Troxel	Troxel Aerospace Industries
2:00 PM	Invited	Invited talk Functional Safety Beyond the Road: Lessons from Autonomous SoC Evolution	Jyotika Athavale	Waymo
2:40 PM	SoCS	Radiation Effects on Versal Network-on-Chip (NoC)	Matthew Cannon	Sandia National Laboratories
3:00 PM	Break			
3:30 PM	SoCS	Mitigating Multi-Bit Error in FPGA BRAM with least hardware overhead	Kamesh Ramani	Siemens EDA
3:50 PM		A Cross-Layer Framework to Evaluate and Improve Radiation Tolerance of AI Workloads on FPGA SoCs	Emre Salman	Stony Brook University
4:10 PM		Closing the Verification Gap: AI-Powered Requirement Verification for FPGA Designs	Adam Taylor	Adiuvo Engineering & Training Ltd
4:30 PM	End of Technical Sessions - 1 Hour Break			
5:30 PM	Industrial Reception			
8:00 PM	End of Wednesday Events			

2026 SEE-SoCS Program Agenda

Thursday, 14 May 2026

Time (PST)	Session	Title	Speaker	Organization
7:30 AM	Registration, 7:30 AM to 4:00 PM			
8:20 AM	Invited	Invited talk: Put a SoC In It! System on Chip Adoption Trends in Space Systems	Ian Troxel	Troxel Aerospace Industries
9:00 AM	SoCS	Evaluating the Edge: SEE and TID Assessment of the NVIDIA Jetson AGX Thor	Michael Felix	UNM COSMIAC/AFRL
9:20 AM		Radiation Testing AI/ML at the SPACER Laboratory	Francisco Viramontes	UNM COSMIAC/AFRL
9:40 AM		Single Event Effects characterization of Frontgrade Gaisler's GR716B radiation-hardened microcontroller	Brian Baranski / Lucas Tambara	Frontgrade Gaisler
10:00 AM	Break			
10:30 AM	SoCS	i.MX 8 SoC as an ISS space radiation monitor data logger	Krzysztof Sielewicz	SigmaLabs Sp. zo.o.
10:50 AM		Fault tolerance on PIC64-HPSC and Moog's Cascade SBC	Mark Broadbent	Moog, Inc.
11:10 AM		SESHAT: A Spacecraft Cryptographic Service Plane on ARM+FPGA SoCs	Mohamed El-Hadedy	California State Polytechnic University, Pomona
11:30 AM		Angular Single-Event Upsets in Heavy Ion Irradiation	David Lee	Sandia National Laboratories
11:50 AM	Lunch			
1:20 PM	Invited	Invited Talk: Do Androids Dream of Martian Skies? Turning a COTS Snapdragon 801 SoC into a Reliable Compute Co-Processor for the Perseverance Rover	Harry Wang	Jet Propulsion Laboratory
2:00 PM	Tutorial	Tutorial Introduction: Did I make the right choice?	Codie Mishler	Northrop Grumman
2:10 PM		Tutorial Module 1: Why We Test for Single Event Effects (SEEs)? With Emphasis on Systems on a Chip (SoCs) and Field Programmable Gate Arrays (FPGAs)	Ken LaBel	Trusted Strategic Solutions, LLC
3:25 PM	Break			
3:45 PM	Tutorial	Tutorial Module 2: Calculating uncertainty in upset rates	Dave Hansen	L3 Harris
5:00 PM	Break			
5:30 PM to 8:00 PM	Poster	Poster Session & Career Networking Reception - Soledad Ballroom		
		SEE Testing at the UCLA PEGASUS Facility	Atharva Kulkarni	UCLA Particle Beam Physics Lab
		SEE Test Results on Telemetry Manager LX7730	Jackson Heun	Microchip
		Single-Event Burnout Mitigation in Beta Ga2O3f Schottky Barrier Diodes Using Field-Plated Metal Ring	Joyprokash Debnath	University of Central Florida
		Radiation Performance Validation of the MAG-PLL00002: Enabling Precision Timing for Next-Generation Space Missions	Anton Quiroz	Magics Technologies
		Single-Event Effects Testing of the ISL75055SLH, ISL73846SLH, and the ISL74324M	Cole Thomson	Renesas
		FULTRA – the new radiation hardened by design 3D PLUS FPGA based processing platform	Patrice Benard	3D Plus
		Altera FPGAs for Mission-Critical Applications: Readiness, Evaluation, and Adoption	Andres Perez Celis	Altera
8:00 PM	End of Thursday Events			

Friday, 15 May 2026

Time (PST)	Session	Title	Speaker	Organization
7:30 AM	Registration, 7:30 to 11:00 AM			
7:45 AM	Tutorial	Tutorial Module 3: Seeing the unseeable: experimental visibility of complex systems	Seth Roffe	Shift5
9:00 AM		Tutorial Module 4: SEE response of SoCs and matching observations to underlying SEEs	Steve Guertin	Jet Propulsion Laboratory
10:15 AM	Break			
10:30 AM	Tutorial	Tutorial Module 5: Better sets of SEE SoC-FPGA data: a checklist approach for test plans and reports	Ken LaBel	Trusted Strategic Solutions, LLC
11:45 AM		Tutorial Chair Wrap up	Codie Mishler	Northrop Grumman Corporation
11:55 AM	Conference Wrap Up		Justin Likar	JHU / APL
12:00 PM	End of Workshop			